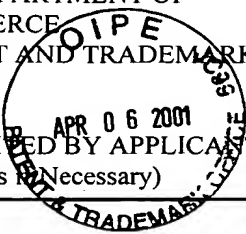


Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO.: 8733.230.00		SERIAL NO.: 09/541,426	
LIST OF REFERENCES CITED BY APPLICANT (Use Several Sheets if Necessary)				APPLICANT: Kyeong Jin KIM and Do Hee KWON			
				FILING DATE: April 3, 2000		GROUP: 2871	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
DN	AA	4,581,608	04/1986	AFTERGUT et al.	340	704	—
DN	AB	4,728,175	03/1988	BARON	350	336	—
DN	AC	4,937,566	06/1990	CLERC	340	784	—
DN	AD	4,978,203	12/1990	YAMAZAKI et al.	350	339 R	—
DN	AE	5,574,582	11/1996	TAKEDA et al.	359	59	—
DN	AF	5,668,650	09/1997	MORI et al.	349	42	—
DN	AG	5,737,051	04/1998	KONDO et al.	349	141	—
DN	AH	5,777,701	07/1998	ZHANG	349	44	—
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
—	AI	0-752-611	01/1997	Europe	NOT IN FILE N/A		
—	AJ	0-814-142	12/1997	Europe	NOT IN FILE N/A		
—	AK	0-854-377	07/1998	Europe	NOT IN FILE N/A		
—	AL	2-296-810	07/1996	UK	NOT IN FILE N/A		
—	AM	2-321-718	08/1998	UK	NOT IN FILE N/A		
—	AN	2-337-843	01/1999	UK	NOT IN FILE N/A		
—	AO	05-297412	11/1993	Japan	Abstract	—	
—	AP	09-197420	07/1997	Japan	Abstract	—	
—	AQ	09-230387	09/1997	Japan	Abstract	—	
—	AR						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
	AS						
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LIST OF REFERENCES CITED BY APPLICANT (Use Several Sheets if Necessary)				APPLICANT: Kyeong Jin KIM, et al.			
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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
DN	AA	5,249,070	05/1993	TAKANO	359	54	—
DN	AB	5,623,354	04/1997	LIEN et al.	349	124	—

FOREIGN PATENT DOCUMENTS					
DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
DN AC	0 884 626	12/1998	Europe	✓	x
DN ✓ AD	961 0774	04/1996	WO	✓	x

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)	
AE	✓ A. Lien, R.A. John, Two-Domain TN-LCDs Fabricated by Parallel Fringe Field Method, SID Digest, 1993, pgs. 269-272
DN AF	✓ A. Lien, R.A. John, TFT-Addressed Two-Domain TN VGA Displays Fabricated Using the Parallel Fringe Field Method, SID Digest, 1994, pgs. 594-597
DN AG	✓ N. Koma, Y. Baba, K. Matsuoka, No-Rub Multi-Domain TFT-LCD Using Surrounding-Electrode Method, SID Digest, 1995, pgs. 869-872
DN AH	✓ H. Murai, M. Suzuki, S. Kaneko, Novel High Contrast Random and Controlled 4-Domain CTN-LCDs with Wide Viewing Angle, Euro Display '96, pgs. 159-161
DN AI	✓ Y. Koike, S. Kataoka, T. Sasaki, H. Chida, H. Tsuda, A. Takeda and K. Ohmuro, T. Sasabayashi, K. Okamoto, A Vertically Aligned LCD Providing Super-High Image Quality, IDW '97, pgs. 159-162
DN AJ	✓ N. Koma, R. Nishikawa, Development of a High-Quality TFT-LCD for Projection Displays, SID Digest, 1997, pgs. 461-464
DN AK	✓ K. Ohmuro, S. Kataoka, T. Sasaki, Y. Koike, Development of Super-High Image Quality Vertical Alignment Mode LCD, SID Digest, 1997, pgs. 845-848

EXAMINER:	DNWYEN	DATE CONSIDERED:	5/16/01
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